

	Type	L #	Hits	Search Text	DBs	Time Stamp
1	BRS	L1	94	(testing same semiconductor) and (semiconductor same empirical)	US- PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWEN T; IBM_TDB	2007/01/28 10:25
2	BRS	L2	44	(testing same semiconductor) and (semiconductor same empirical same data)	US- PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWEN T; IBM_TDB	2007/01/28 10:27
3	BRS	L3	724	(simulation same empirical same data)	US- PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWEN T; IBM_TDB	2007/01/28 10:28
4	BRS	L4	32	(simulation same empirical same data same semiconductor)	US- PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWEN T; IBM_TDB	2007/01/28 10:28